

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/652,862	CHANG ET AL.	
Examiner	Art Unit	
James D. Ewart	2617	

	SEAR	CHED	·
Class	Subclass	Date	Examiner
455	12.1	4/24/2006	JDE
	13.1		
	427		
	429		
	456		
	458		
	562		
342	357.01		
	357.16		
	457		
244	158R		

ERFERENC	CE SEARCH	ED
Subclass	Date	Examiner
above	4/24/2006	JDE
L		
	Subclass	

DATE	EXMR
	l